

RF POWER MOSFETs N-CHANNEL ENHANCEMENT MODE

The ARF467FL is a rugged high voltage RF power transistor designed for scientific, commercial, medical and industrial RF power amplifier applications up to 45 MHz. It has been optimized for both linear and high efficiency classes of operation.

• Specified 150 Volt, 40.68 MHz Characteristics:

Output Power = 300 Watts.

Gain = 16dB (Class AB)

Efficiency = 75% (Class C)

- Low Cost Flangeless RF Package.
- Low Vth thermal coefficient.
- Low Thermal Resistance.
- Optimized SOA for Superior Ruggedness.

MAXIMUM RATINGS

MAXIMUM RATINGS		All Ratings: $T_C = 25^{\circ}C$ unless otherwise specified.		
Symbol	Parameter	ARF467FL	UNIT	
V _{DSS}	Drain-Source Voltage	1000	Volts	
V _{DGO}	Drain-Gate Voltage	1000	Volts	
I _D	Continuous Drain Current @ T _C = 25°C	12	Amps	
V _{GS}	Gate-Source Voltage	±30	Volts	
P _D	Total Power Dissipation @ T _C = 25°C	425	Watts	
$R_{_{ ext{ heta}JC}}$	Junction to Case	0.35	°C/W	
T_,T _{STG}	Operating and Storage Junction Temperature Range	-55 to 175	- °C	
TL	Lead Temperature: 0.063" from Case for 10 Sec.	300		

STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	ТҮР	MAX	UNIT	
BV _{DSS}	Drain-Source Breakdown Voltage ($V_{GS} = 0V, I_{D} = 250 \mu A$)	1000			Volts	
R _{DS(ON)}	Drain-Source On-State Resistance $(1)(V_{GS} = 10V, I_{D} = 6.5A)$			1.0	ohms	
	Zero Gate Voltage Drain Current ($V_{DS} = 1000V, V_{GS} = 0V$)			25		
DSS	Zero Gate Voltage Drain Current ($V_{DS} = 800V$, $V_{GS} = 0V$, $T_{C} = 125^{\circ}C$)			250	μΑ	
I _{GSS}	Gate-Source Leakage Current ($V_{GS} = \pm 30V$, $V_{DS} = 0V$)			±100	nA	
9 _{fs}	Forward Transconductance ($V_{DS} = 25V$, $I_{D} = 6.5A$)	4	6	9	mhos	
V _{GS} (TH)	Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_{D} = 1mA$)	3		5	Volts	

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

DYNAMIC CHARACTERISTICS

Symbol	Characteristic	Test Conditions	MIN	ТҮР	МАХ	UNIT
C _{iss}	Input Capacitance	V _{GS} = 0V		1900		
C _{oss}	Output Capacitance	$V_{DS} = 50V$		230		pF
C _{rss}	Reverse Transfer Capacitance	f = 1 MHz		40		
t _{d(on)}	Turn-on Delay Time	V _{GS} = 15V		12		
t _r	Rise Time	V _{DD} = 500 V		8		ns
t _{d(off)}	Turn-off Delay Time	I _D = 12A @ 25°C		41		
t _f	Fall Time	R _G = 1.6Ω		10		

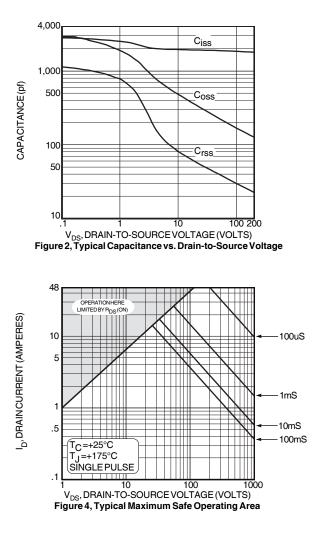
FUNCTIONAL CHARACTERISTICS

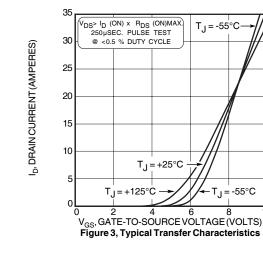
Symbol	Characteristic	Test Conditions	MIN	ТҮР	МАХ	UNIT
G _{PS}	Common Source Amplifier Power Gain	f = 40.68 MHz	14	16		dB
η	Drain Efficiency	$V_{GS} = 2.5V$ $V_{DD} = 150V$	70	75		%
ψ	Electrical Ruggedness VSWR 10:1	P _{out} = 300W	No Deg	radation	in Output	Power

(1) Pulse Test: Pulse width < 380 μ S, Duty Cycle < 2%

Microsemi reserves the right to change, without notice, the specifications and information contained herein.

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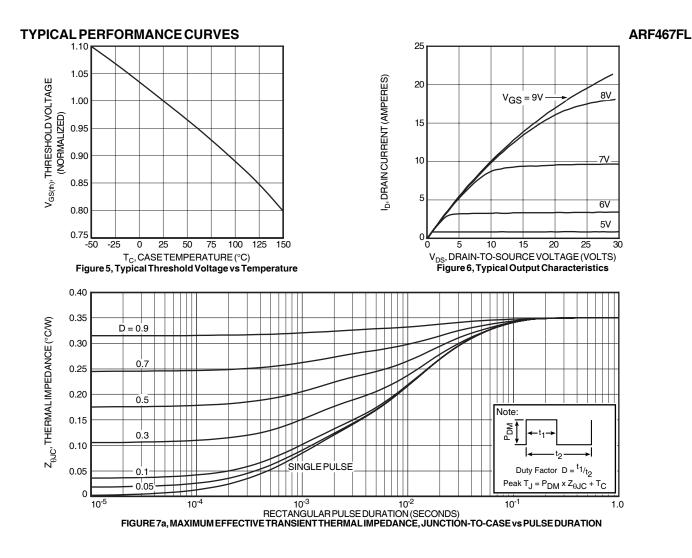




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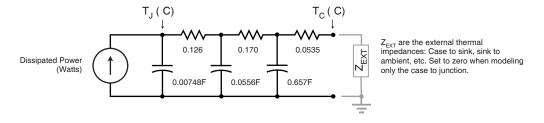
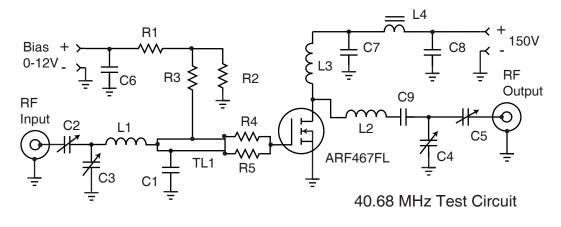




Table 1 - Typical Class AB Large Signal Input - Output Imp	bedance
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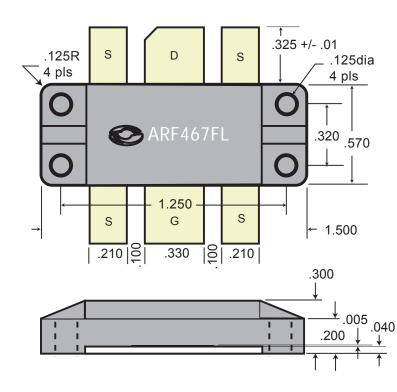
Freq. (MHz)	Z _{IN} (Ω)	Z _{OL} (Ω)
2.0	18 - j 11	30 - j 1.7
13.5	1.3 - j 5	25.7 - j 9.8
27.1	.40 - j 2.6	18 - j 13.3
40.7	.20 - j 1.6	12 - j 12.6
65	.11 + j 0.6	6.2 - j 8.9

 $Z_{in}~$ - Gate shunted with 25 Ω $$I_{DQ}$$ = 100mA Z_{OL} - Conjugate of optimum load for 300 W output at V_{dd} = 150V



C1 -- 2200pF ATC 700B C2-C5 -- Arco 465 Mica trimmer C6-C8 -- .1 μF 500V ceramic chip C9 -- 3x 2200pF 500V chips COG L1 -- 3t #22 AWG .25"ID .25 "L ~55nH L2 -- 5t #16 AWG .312" ID .35"L ~176nH L3 -- 10t #24 AWG .25"ID ~.5uH L4 -- VK200-4B ferrite choke 3uH $\begin{array}{l} \text{R1- R3 -- } 1 k\Omega \ 0.5W \\ \text{R4- R5 -- } 1\Omega \ 1W \ \text{SMT} \\ \text{TL1 -- } 40\Omega \ \text{t-line} \ 0.15 \ \text{x} \ 2" \\ \text{C1 is} \ \sim 1.75" \ \text{from} \ \text{R4-5}. \end{array}$

T3 Package Outline



Thermal Considerations and Package Mounting:

The rated power dissipation is only available when the package mounting surface is at 25 C and the junction temperature is 175 C. The thermal resistance between junctions and case mounting surface is 0.3 C/W. When installed, an additional thermal impedance of 0.17 C/W between the package base and the mounting surface is typical. Insure that the mounting surface is smooth and flat. Thermal joint compound must be used to reduce the effects of small surface irregularities. Use the minimum amount necessary to coat the surface. The heatsink should incorporate a copper heat spreader to obtain best results.

The package design clamps the ceramic base to the heatsink. A clamped joint maintains the required mounting pressure while allowing for thermal expansion of both the base and the heat sink. Four 4-40 (M3) screws provide the required mounting force. Torque the mounting screws to 6 in-lb (0.68 N-m).

HAZARDOUS MATERIAL WARNING

The white ceramic portion of the device between leads and mounting surface is beryllium oxide, BeO. Beryllium oxide dust is toxic when inhaled. Care must be taken during handling and mounting to avoid damage to this area. These devices must never be thrown away with general industrial or domestic waste.

Microsemi's products are covered by one or more of U.S.patents 4,895,810 5,045,903 5,089,434 5,182,234 5,019,522 5,262,336 6,503,786 5,256,583 4,748,103 5,283,202 5,231,474 5,434,095 5,528,058 6,939,743 and foreign patents. US and Foreign patents pending. All Rights Reserved.

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